

IRISH STANDARD

I.S. CLC/TS 50466:2006

ICS 31.020

LONG DURATION STORAGE OF

ELECTRONIC COMPONENTS
SPECIFICATION FOR IMPLEMENTATION

National Standards Authority of Ireland Glasnevin, Dublin 9 Ireland

Tel: +353 1 807 3800 Fax: +353 1 807 3838 http://www.nsai.ie

Sales

http://www.standards.ie

This Irish Standard was published under the authority of the National Standards Authority of Ireland and comes into effect on: June 6, 2006

NO COPYING WITHOUT NSAI PERMISSION EXCEPT AS PERMITTED BY COPYRIGHT LAW

© NSAI 2006 Price Code J

Údarás um Chaighdeáin Náisiúnta na hÉireann

This is a free page sample. Access the full version online.

TECHNICAL SPECIFICATION SPÉCIFICATION TECHNIQUE TECHNISCHE SPEZIFIKATION

CLC/TS 50466

May 2006

ICS 31.020

English version

Long duration storage of electronic components – Specification for implementation

Stockage longue durée des composants électroniques – Guide de mise en oeuvre

Langzeitlagerung von elektronischen Bauelementen – Spezifikation für die Ausführung

This Technical Specification was approved by CENELEC on 2005-12-03.

CENELEC members are required to announce the existence of this TS in the same way as for an EN and to make the TS available promptly at national level in an appropriate form. It is permissible to keep conflicting national standards in force.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

This Technical Specification was prepared by the Technical Committee CENELEC TC 107X, Process management for avionics.

The text of the draft was submitted to the formal vote and was approved by CENELEC as CLC/TS 50466 on 2005-12-03.

The following date was fixed:

latest date by which the existence of the CLC/TS has to be announced at national level

(doa) 2006-06-03

This document, which is in line with IEC/PAS 62435 relating to the management of obsolescence of electronic components, is first of all a practical guide to methods of long duration storage (more than 5 years) which summarizes the existing practices in the industry.

The application of the approach proposed in this guide in no way guarantees that the stored components are in perfect operating condition at the end of this storage. It only comprises a means of minimizing potential and probable degradation factors.

Unless otherwise specified, the approach, as well as the methods presented apply to all families of electronic components:

- passive components, including quartz crystals, connectors and relays. However, components with "manufacturer's" specifications showing an expiry date, or specific storage conditions, are excluded from this guide (e.g. primary cells, storage cells, etc...),
- encapsulated or non-encapsulated active components of a silicon [Si] or gallium arsenide [GaAs] technology,
- micro-electronic assemblies.

Contents

1	Gene	eral		5			
2	Norm	native ref	ferences	5			
3	Stora	ige decis	sion criteria	6			
	3.1	Advantages of storage					
		3.1.1	Technical simplicity – Rapidity	6			
		3.1.2	Solution durability				
		3.1.3	Preventive storage				
	3.2		ds – Drawbacks				
		3.2.1	Generic aging hazard				
		3.2.2	Poor stock dimensioning.				
		3.2.3	Incorrect control of reliability during storage				
		3.2.4	Freezing equipment functionalities				
	3.3	_	e cost (Annex C)				
	3.4 Decision criteria						
1			rocurement				
4	4.1	• .					
	4.1		componentsty of components to be stored				
	4.2	4.2.1					
		4.2.1	Production stock				
	4.0		Field service stock				
	4.3		is it worth keeping in stock?				
_	4.4		ement recommendations				
5			alidation of the components				
	5.1	•	se				
	5.2		ınt field				
	5.3		election criteria				
	5.4		rements and tests				
		5.4.1	Sampling				
		5.4.2	Visual examination, sealing, solderability				
		5.4.3	Compliance with the electrical specifications				
			5.4.3.1 Measurement of electrical parameters	11			
			5.4.3.2 Temperature impact	12			
		5.4.4	Assessment of the supplied batch reliability	12			
		5.4.5	Manufacturing control check (technological analysis)	14			
	5.5	Sanctio	on	14			
6	Cond	litioning a	and storage	14			
	6.1	Type of	f environment	14			
	6.2	P. Elementary storage unit					
	6.3	· · · ·					
	6.4	•					
	6.5	•					
	6.6	•					
	6.7						
	6.8	·					
	6.9	Storage conditions					
	0.0	6.9.1	Storage area				
		6.9.2	Temperature				
		6.9.3	Temperature variations				
		6.9.4	Relative humidity - Chemical attacks - Contamination				
		6.9.5	Pressure				
		6.9.6	Electrostatic discharges	1 /			

		6.9.7	Vibrations – Mechanical impacts	17	
		6.9.8	Electromagnetic field - Radiation	17	
		6.9.9	Light	17	
	6.10			17	
7	Periodic check of the components				
	7.1	Objectives			
	7.2	Periodicity			
	7.3	Tests of	during periodic check	18	
8	De-stocking				
	8.1	Precau	ıtions	18	
		8.1.1	Electrostatic discharges	19	
		8.1.2	Mechanical impacts	19	
	8.2	Inspec	tion	19	
9	Feed	fback		19	
Anr	nex A -	– Exam _l	ple related to components	20	
	A.1	Exampl	e of a component list	20	
	A.2	Data de	scription	21	
Anr	nex B -	– Examı	oles of periodic and/or destocking tests	22	
Anı	nex C	– Parar	meters influencing the final price of the component storage	24	
Anr	nex D	– Paran	neters influencing the quantity of the components to be stored	25	
Anr	nex E -		e mechanisms - Hermetically encapsulated and		
		non-e	ncapsulated active components	26	
Anr	nex F -	- Failure	e mechanisms: GaAs components	28	
Bib	liograp	hy		30	
Tal	ole E.		ure mechanisms - Hermetically encapsulated		
			non-encapsulated active components		
			ure modes compared with initial table on the silicon devices		
Tak	ole F 2	2 – Failı	re modes specific to GaAs components	29	



The is a new provider i arenade and chare publication at the limit below	This is a free preview.	Purchase the	entire publication	at the link below:
--	-------------------------	--------------	--------------------	--------------------

Product Page

- Dooking for additional Standards? Visit Intertek Inform Infostore
- Dearn about LexConnect, All Jurisdictions, Standards referenced in Australian legislation